Notice of References Cited

Application/Control No. O9/827,676

Examiner
Quang D Vu

Applicant(s)/Patent Under Reexamination TANAKA ET AL.

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,281,552	08-2001 (Kawasaki et al.	257/59
	В	US-5,726,461 /.	03-1998	Shimada-et al.	257/59
	С	US-5,103,330	04-1992	Fakami et al.	257/59
	D	US-6,358,766 /	03-2002	Kasahara	438/149
	Е	US-0000555 /	01-2002	Fujikawa et al.	257/59
	F	US-6,218,206	04-2001	Inoue et al.	438/159
	G	US-			
	Н	US-			
	I,	US-			
	J	US-			
	К	US-			
	L	US-			
-	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under Reexamination Application/Control No. 10/051,267 TANAKA ET AL. Art Unit Examiner Page 1 of 1 2811

Notice of References Cited

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Thien F Tran

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,246,070	06-2001	Yamazaki et al.	257/347
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-		•	
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.